

Notice of References Cited	Application/Control No. 10/647,520	Applicant(s)/Patent Under Reexamination CHOI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,458,297 A	07-1969	ANDERSON ROLLAND L	48/189.4
	B	US-4,167,987 A	09-1979	Turner, William F.	181/235
	C	US-4,167,986 A	09-1979	Conway, James R.	181/224
	D	US-4,274,386 A	06-1981	Reyes, Jose	123/591
	E	US-4,333,441 A	06-1982	Still et al.	48/189.4
	F	US-4,362,223 A	12-1982	Meier, Irmhild	181/206
	G	US-4,672,940 A	06-1987	Nakayama et al.	123/590
	H	US-5,113,838 A	05-1992	Kim, Sei Y.	123/592
	I	US-5,952,624 A	09-1999	Hornback et al.	181/255
	J	US-5,970,963 A	10-1999	Nakase et al.	123/590
	K	US-6,035,964 A	03-2000	Lange, Kurt-Jurgen	181/224
	L	US-6,439,540 B1	08-2002	Tse, Man-Chun	251/127
	M	US-6,550,446 B1	04-2003	Robley, Jr., Spencer H	123/306

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 01019163 A	01-1989	Japan	SUKIMOTO et al.	F02M 35/10
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2,708,006 A	05-1955	FREDRIK BACKMAN HANS	181/225
	B	US-3,365,863 A	01-1968	GREIPEL FRANK J; et. al.	96/386
	C	US-5,595,157 A	01-1997	Siew et al.	123/306
	D	US-5,947,081 A	09-1999	Kim, Sei Y.	123/306
	E	US-6,158,412 A	12-2000	Kim, Jay S.	123/306
	F	US-6,267,006 B1	07-2001	Bugli et al.	73/118.2
	G	US-6,536,420 B1	03-2003	Cheng, Theodore Y.	123/590
	H	US-2003/0140892 A1	07-2003	Kim, Sei Young	123/306
	I	US-6,796,296 B2	09-2004	Kim, Jay S.	123/590
	J	US-2004/0211389 A1	10-2004	DeLisle, Gilles L.	123/306
	K	US-6,840,212 B2	01-2005	Kim, Sei Young	123/306
	L	US-6,901,907 B2	06-2005	Wijaya, Heru Prasanta	123/306
	M	US-6,928,979 B2	08-2005	Chen, Yung-Tsung	123/306

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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	U	
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	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,177,972 A	04-1965	WIRT LESLIE S	181/268
	B	US-D355,420 S	02-1995	Cho, Byoung M.	D15/5
	C	US-5,916,134 A	06-1999	Yang et al.	60/299
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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